

Various microcavity lasers monolithically grown on planar on-axis Si (001) substrates

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Abstract— With exponential growth in data traffic and limitations of Moore’s Law, electronic integrated circuits have reached a bottleneck period. Photonic Integrated Circuits (PICs) are seemed as candidate for solving the problem of data transmission. Moreover, robust laser sources are significant building block for PICs design. Here, we demonstrate several InAs/GaAs quantum dot microcavity lasers monolithically grown on planar on-axis Si (001) substrates, including microdisk cavity [1], 2D Photonic Crystal with L3 defects cavity [2], 1D Photonic Crystal nanobeam cavity, bandedge Photonic Crystal cavity, bound states in the continuum (BIC) cavity, etc.

Keywords—microcavity lasers, PICs, quantum dot material, Si substrates

I. EXTENDED ABSTRACTS

The recent development of data transmission speed of electronic integrated circuits has been reaching a bottleneck due to electron tunnelling and huge power consumption. However, Si-based Photonic Integrated Circuits not only offer advantages such as high modulation speed, low power consumption, low thermal effects, large integration capacity, but also can be made with the same fabrication technique as CMOS-based electronic integrated circuits [3-5]. Silicon photonics technology has monolithically integrated optical components such as modulators, waveguides, beam splitters, detectors, etc. But monolithically integrated the light source of the core component, that is, semiconductor laser is still a tricky challenge, due to the conjunction of large thermal expansion coefficients, lattice, and polarity mismatches between the Si substrate and III-V layer [6-8]. Despite several techniques have been used in heterogeneous integration of microcavity lasers on Silicon or Silicon on insulator (SOI) substrates, such as wafer bonding, transfer printing, etc [9-11]. The monolithic integration is still the efficient way for a higher yield, higher density and higher

scalability for III-V microcavity lasers integrated on CMOS compatible Silicon substrates. By optimizing the III-V materials buffer layer and complex epitaxial technology, great efforts have been made to achieve a low defect density and CMOS compatible III-V/Si virtual substrate [12]. In addition, using zero-dimensional III-V quantum dots (QDs) as gain material provide various advantages, including less sensitivity to defects, low lasing threshold, high performance at room temperature and long lifetime [13]. Due to the reduced non-radiative recombination rate, the realization of high-quality QDs insensitive to defects as a gain material is the best solution for high-efficiency light-emitting sources monolithically grown on Si substrates [14].

Here, we demonstrate several kinds of InAs/GaAs quantum dot microcavity lasers fabricated on CMOS-compatible on-axis Si (001) substrates, all the lasers’ pumping condition is CW optically pumped using a 632.8 nm He-Ne laser with focus spot size of $\sim 3 \mu\text{m}$ at room temperature.

1. **Microdisk lasers** [1]. Fig.1.(a) presents the measured lasing spectra of ultra-small microdisk lasers with diameter $\sim 1.1 \mu\text{m}$ and $1.4 \mu\text{m}$. The L-L curve and full width at half maximum (FWHM) shows in Fig.1.(b), which presents ultra-low threshold of the first excited state is $2.9 \pm 0.4 \mu\text{W}$. From Fig.1.(a), we can also find the mode selection by changing the diameter of microdisk cavity, owing to its large free spectral range (FSR) and well-separated resonant peaks.
2. **2D Photonic Crystal with L3 defects lasers** [2]. The measured spectra under various pumping powers of a single mode Photonic Crystal laser with $a = 310\text{nm}$ and $r/a = 0.27$ is shown in Fig.2.(a). The collected intensity (L-L) and the FWHM of the lasing peak at $\sim 1306 \text{ nm}$ under various pumping powers are shown in Fig.2.(b), which exhibit the

evidence of the lasing with a clear kink of L-L curve and the spectral linewidth narrowing effect.

- 1D Photonic Crystal nanobeam lasers.** The ultra-small physical volume of $\sim 0.64 \lambda^3$ ($\lambda = 1313\text{nm}$) is obtained. The nanobeam cavity measured spectra shows single mode at $\sim 1313\text{nm}$ with pumping threshold of $\sim 0.8 \mu\text{W}$. The FWHM of nanobeam cavity is below 1 nm when it reaches threshold. Due to the paper haven't been published yet, we would not show the figure of measured spectra.
- Bandedge Photonic Crystal lasers.** With the designed band gap, we have three bandedge point M_1 , M_2 , X_1 with low group velocity. Under the pumping condition, we obtained relative high pumping threshold of $\sim 4 \mu\text{W}$, as well as large linewidth of $\sim 4 \text{nm}$. With low side mode suppression ratio (SMSR) and relative large full width at half-maximum (FWHM), we still need to optimize fabrication process.

In conclusion, all these kind of microcavity lasers show a major advance towards large-scale, low-cost integration of laser sources on the Silicon platform.

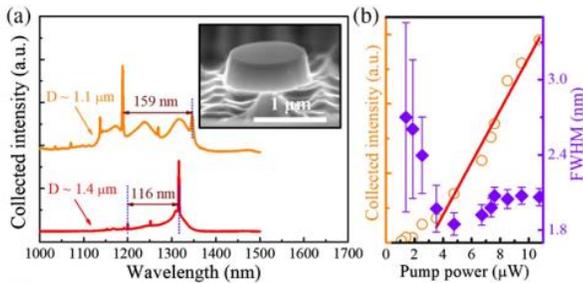


Fig.1.(a) Measured lasing spectra of the microdisk lasers with diameter $\sim 1.1 \mu\text{m}$ and $1.4 \mu\text{m}$. (b) L-L curve and FWHM of lasing peak $\sim 1189 \text{nm}$ of the sub-wavelength scale microdisk laser with $D \sim 1.1 \mu\text{m}$.

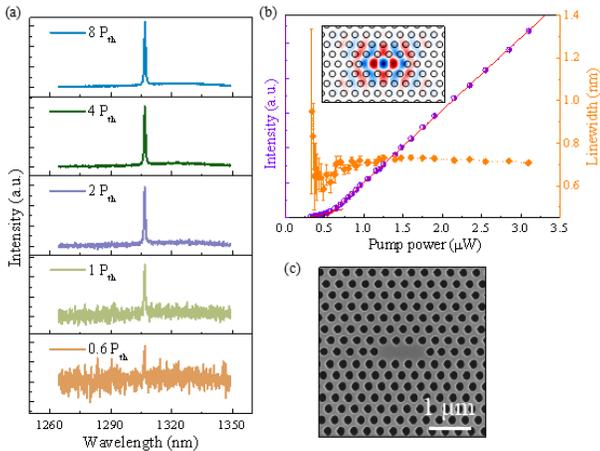


Fig.2.(a) Measured spectra under various input pumping powers of the PC laser with $a = 310 \text{nm}$ and $r/a = 0.27$. (b) Collected L-L curve and line width of the lasing peak at 1306nm . The inset shows the calculated E_y field profile of the fundamental mode. (c) Top-view SEM image of the fabricated PC cavity.

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